

#### < IGBT MODULES >

## CM400C1Y-24S

HIGH POWER SWITCHING USE INSULATED TYPE

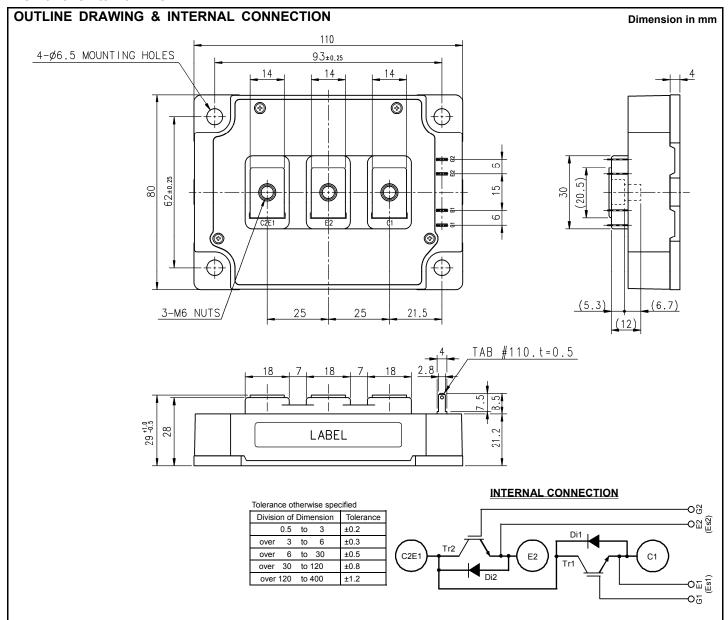


**Dual (AC switch)** 

- Flat base Type
- Copper base plate
- •RoHS Directive compliance
- •UL Recognized under UL1557, File E323585
- \*. DC current rating is limited by power terminals.

#### **APPLICATION**

AC Power Switch for NPC



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ABSOLUTE MAXIMUM RATINGS ( $T_j$ =25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1200	V	
V <sub>GES</sub>	Gate-emitter voltage	C-E short-circuited	±20	V	
Ic	Collector current	DC, T <sub>C</sub> =124 °C (Note.2, 4)	350 *	Α	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note.3)	800	] ^	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note.2, 4)	2670	W	
I <sub>E</sub> (Note.1)	Emitter current	T <sub>C</sub> =25 °C (Note.2, 4)	350 *	^	
I <sub>ERM</sub> (Note.1)	Emilier current	Pulse, Repetitive (Note.3)	800	A	
V <sub>isol</sub>	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	2500	V	
T <sub>jmax</sub>	Maximum junction temperature	-	175	°C	
T <sub>cmax</sub>	Maximum case temperature	(Note.2)	125		
T <sub>jopr</sub>	Operating junction temperature	-	-40 ~ +150	°C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +125		

ELECTRICAL CHARACTERISTICS (T<sub>j</sub>=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Conditions		Limits		
Зуппоп	item	Conditions			Тур.	Max.	Unit
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited		-	-	1.0	mA
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	-	0.5	μΑ
$V_{\text{GE(th)}}$	Gate-emitter threshold voltage	I <sub>C</sub> =40 mA, V <sub>CE</sub> =10 V		5.4	6.0	6.6	V
		I <sub>C</sub> =400 A (Note.5),	T <sub>j</sub> =25 °C	-	1.85	2.30	V
		V <sub>GE</sub> =15 V,	T <sub>j</sub> =125 °C	-	2.05	-	
\/	Collector emitter acturation valtage	Terminal	T <sub>j</sub> =150 °C	-	2.10	-	
$V_{CEsat}$	Collector-emitter saturation voltage	I <sub>C</sub> =400 A (Note.5),	T <sub>j</sub> =25 °C	-	1.70	2.15	
		V <sub>GE</sub> =15 V,	T <sub>j</sub> =125 °C	-	1.90	-	V
		Chip	T <sub>j</sub> =150 °C	-	1.95	-	
Cies	Input capacitance	V <sub>CE</sub> =10 V, G-E short-circuited		-	-	40	nF
Coes	Output capacitance			-	-	8.0	
Cres	Reverse transfer capacitance		-	-	0.66		
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =600 V, I <sub>C</sub> =400 A, V <sub>GE</sub> =15 V		-	934	-	nC
t <sub>d(on)</sub>	Turn-on delay time	$V_{CC}$ =600 V, $I_{C}$ =400 A, $V_{GE}$ =±15 V, $R_{G}$ =0 $\Omega$ , Inductive load		-	-	800	ns
tr	Rise time			-	-	200	
t <sub>d(off)</sub>	Turn-off delay time			-	-	600	
t <sub>f</sub>	Fall time			-	-	300	
		I <sub>E</sub> =400 A (Note.5),	T <sub>j</sub> =25 °C	-	1.85	2.30	
	Emitter-collector voltage	G-E short-circuited,	T <sub>j</sub> =125 °C	-	1.85	-	V
V <sub>EC</sub> (Note.1)		Terminal	T <sub>j</sub> =150 °C	-	1.85	-	
V <sub>EC</sub> `		I <sub>E</sub> =400 A (Note.5),	T <sub>j</sub> =25 °C	-	1.70	2.15	V
		G-E short-circuited,	T <sub>j</sub> =125 °C	-	1.70	-	
		Chip	T <sub>j</sub> =150 °C	-	1.70	-	
t <sub>rr</sub> (Note.1)	Reverse recovery time	V <sub>CC</sub> =600 V, I <sub>E</sub> =400 A, V <sub>GE</sub> =±15 V,		-	-	300	ns
Q <sub>rr</sub> (Note.1)	Reverse recovery charge	R <sub>G</sub> =0 Ω, Inductive load		-	21.4	-	μC
Eon	Turn-on switching energy per pulse	V <sub>CC</sub> =600 V, I <sub>C</sub> =I <sub>E</sub> =400 A,		-	39.8	-	!
E <sub>off</sub>	Turn-off switching energy per pulse	$V_{GE}$ =±15 V, $R_{G}$ =0 $\Omega$ ,		-	44.9	-	mJ
E <sub>rr</sub> (Note.1)	Reverse recovery energy per pulse	T <sub>i</sub> =150 °C, Inductive load		-	35.2	-	mJ
r <sub>g</sub>	Internal gate resistance	Per switch		-	4.9	-	Ω

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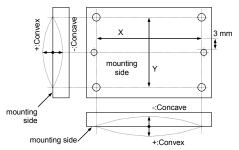
#### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
			Min.	Тур.	Max.	Offic
$R_{th(j-c)Q}$	Thermal resistance (Note.2)	Junction to case, per IGBT	-	-	56	K/kW
$R_{th(j-c)D}$		Junction to case, per FWDi	-	-	95	K/kW
R <sub>th(c-s)</sub>	Contact thermal resistance (Note.2)	Case to heat sink, per 1/2 module, Thermal grease applied (Note.6)	-	18	-	K/kW

#### **MECHANICAL CHARACTERISTICS**

Symbol	Item	Conditions		Limits			Unit
	item			Min.	Тур.	Max.	Offic
M <sub>t</sub>	Mounting torque	Main terminals	M 6 screw	3.5	4.0	4.5	N·m
Ms		Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N·m
m	Weight	-		ı	580	-	g
ec	Flatness of base plate	On the centerline X, Y (Note.7)		-100	-	+100	μm

- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free wheeling diode (FWDi).
  - 2. Case temperature (T<sub>c</sub>) and heat sink temperature (T<sub>s</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
    - The heat sink thermal resistance should measure just under the chips.
  - 3. Pulse width and repetition rate should be such that the device junction temperature (T<sub>i</sub>) dose not exceed T<sub>jmax</sub> rating.
  - 4. Junction temperature  $(T_i)$  should not increase beyond  $T_{jmax}$  rating.
  - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
  - 6. Typical value is measured by using thermally conductive grease of  $\lambda$ =0.9 W/(m·K).
  - 7. Base plate (mounting side) flatness measurement points (X, Y) are as follows of the following figure.



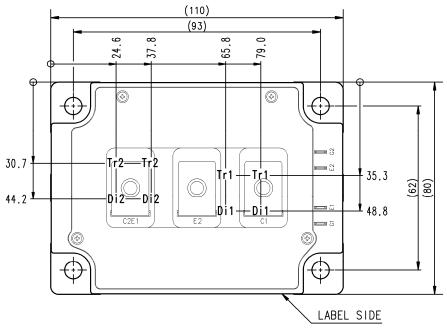
\*. DC current rating is limited by power terminals.

#### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Item	Conditions	Limits			Unit
	item	Conditions	Min.	Тур.	Max.	Oill
V <sub>CC</sub>	(DC) Supply voltage	Applied across C1-E2	1	600	850	٧
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2	13.5	15.0	16.5	٧
$R_G$	External gate resistance	Per switch	0	-	10	Ω

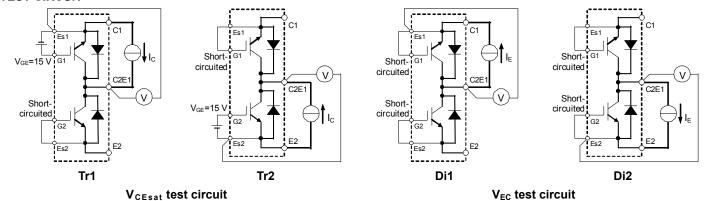
#### **CHIP LOCATION (Top view)**

Dimension in mm, tolerance: ±1 mm

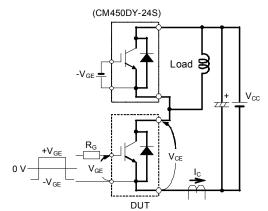


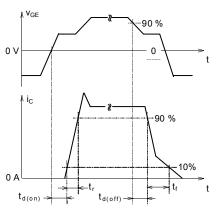
Tr1/Tr2: IGBT, Di1/Di2: FWDi

#### **TEST CIRCUIT**

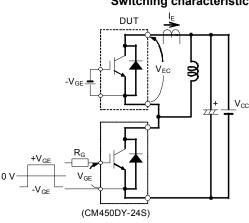


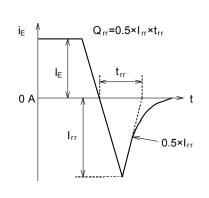
#### **TEST CIRCUIT AND WAVEFORMS**



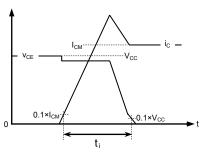


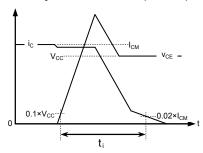
Switching characteristics test circuit and waveform

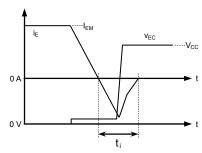




Reverse recovery characteristics (t<sub>rr</sub>, Q<sub>rr</sub>) test circuit







IGBT Turn-on switching energy

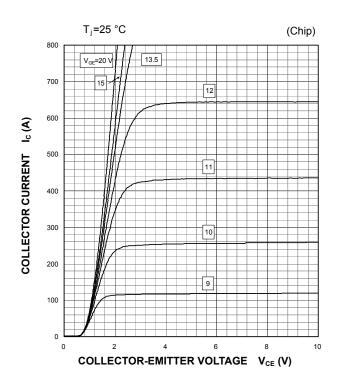
**IGBT Turn-off switching energy** 

FWDi Reverse recovery energy

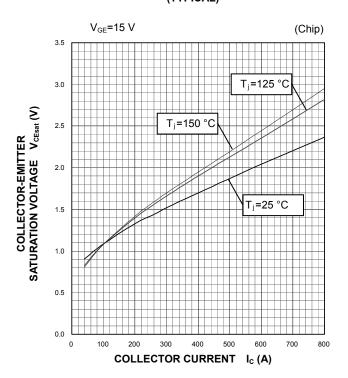
Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

#### **PERFORMANCE CURVES**

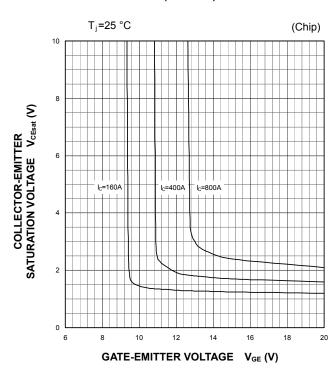
## OUTPUT CHARACTERISTICS (TYPICAL)



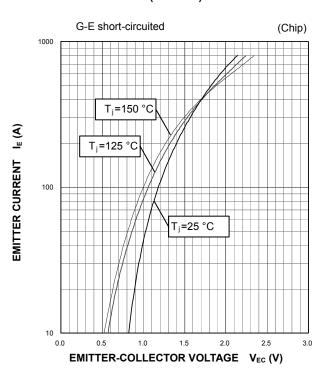
#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



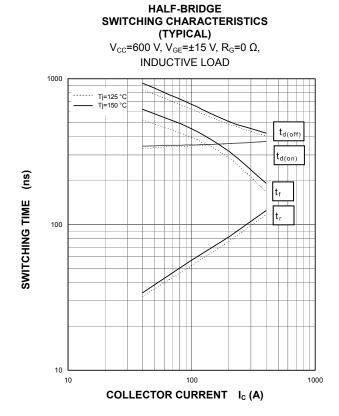
#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)

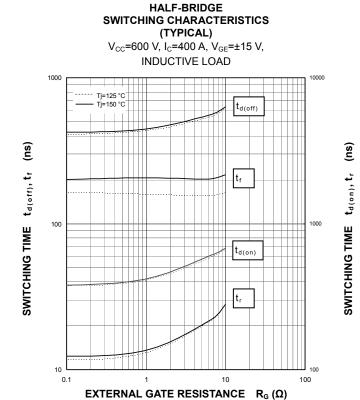


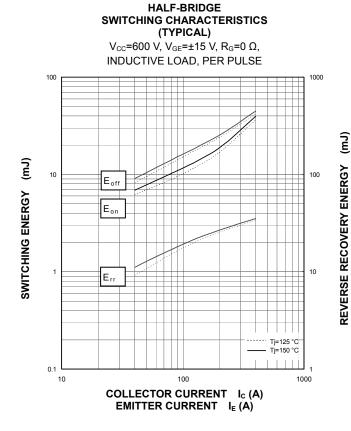
#### FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)

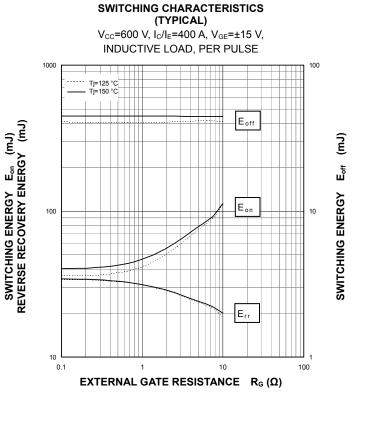


#### **PERFORMANCE CURVES**







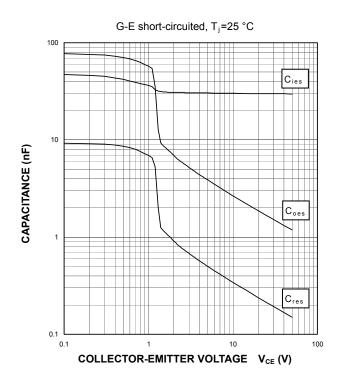


**HALF-BRIDGE** 

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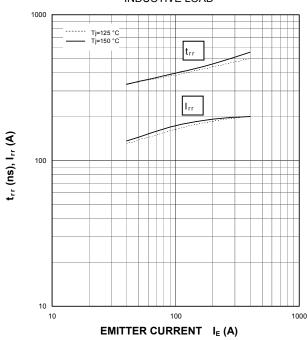
#### **PERFORMANCE CURVES**

## CAPACITANCE CHARACTERISTICS (TYPICAL)

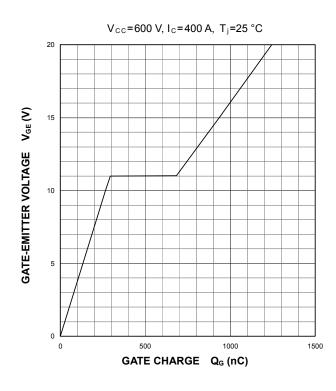


## FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL) Vcc=600 V. VcE=±15 V. Rc=0 Ω.

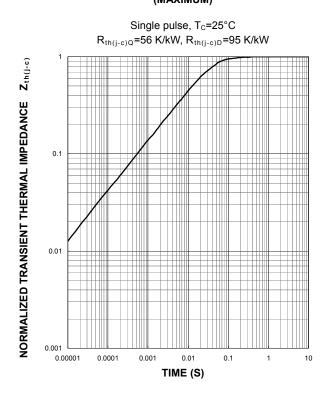
 $V_{\text{CC}}$ =600 V,  $V_{\text{GE}}$ =±15 V,  $R_{\text{G}}$ =0  $\Omega$ , INDUCTIVE LOAD



## GATE CHARGE CHARACTERISTICS (TYPICAL)



## TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



#### Keep safety first in your circuit designs!

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